

#### **Features**

- 1206 SMD LED
- Close responsively to the human eye spectrum
- Light to Current, analog output
- Good output linearity across wide illumination range
- Low sensitivity variation across various light sources

# **Applications**

- Infrared application system
- Optoelectronic automatic control system
- Optoelectronic switch
- Printer
- Counters and sorters
- Encoders
- Floppy disk drive
- Video camera, tape and card readers
- Position sensors

# **Description**

The IN-S126BTNPT is a popular 1206 package with versatile design capabilities. It is a PCB type LED which can be used in various applications. Due to its **black** epoxy, the device is matched to visible light and infrared radiation.

## **Recommended Solder Pattern**

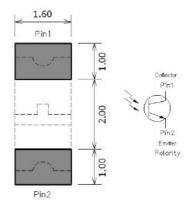
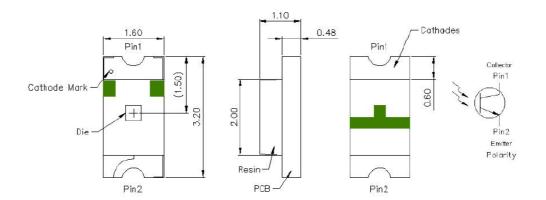


Figure 1. IN-S126BTNPT Solder Pattern

# Package Dimensions in mm



#### Notes.

- 1. All dimensions are in millimeters.
- 2. Tolerance is ± 0.10 mm unless otherwise noted

Figure 2. IN-S126BTNPT Package Dimensions



# Absolute Maximum Rating at 25°C

Symbol	Parameters	Ratings	Units	Notes
BVCEO	Collector-Emitter Breakdown Voltage	35	V	1
BVECO	Emitter-Collector Breakdown Voltage	5	V	2
lc	Collector Current	20	mA	
Topr	Operating Temperature	-40~+85	°C	
Tstg	Storage Temperature	-40~+100	°C	
Tsol	Soldering Temperature	260	°C	3
Pto	Total Power Dissipation	150	mW	

#### **Notes**

- 1. Test conditions: Ic=100µA, Ee=0mW/cm2.
- 2. Test conditions:  $I_E=100\mu A$ ,  $E_e=0mW/cm_2$ .
- 3. Soldering time  $\leq$  5 seconds.

#### **ESD Precaution**

ATTENTION: Electrostatic Discharge (ESD) protection



The symbol above denotes that ESD precaution is needed. ESD protection for GaP and AlGaAs based chips is necessary even though they are relatively safe in the presence of low static-electric discharge. Parts built with AllnGaP, GaN, or/and InGaN based chips are STATIC SENSITIVE devices. ESD precaution must be taken during design and assembly.

If manual work or processing is needed, please ensure the device is adequately protected from ESD during the process.

Please be advised that normal static precautions should be taken in the handling and assembly of this device to prevent damage or degradation which may be induced by electrostatic discharge (ESD).

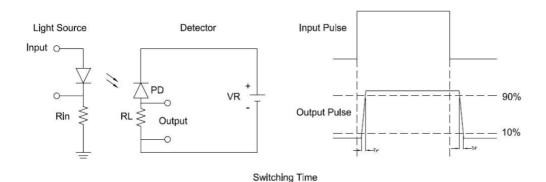


# **Electro-Optical Characteristics**

Symbol	Parameters	Test conditions	Min	Тур	Max	Units	Notes
λD	Rang Of Spectral Bandwidth		750	-	1100	nm	
λР	Wavelength Of Peak Sensitivity		-	940		nm	
BVCEO	Collector-Emitter Breakdown Voltage	Ic=100µA E <sub>e</sub> =0mW/cm²	-	30	-	V	
BVECO	Emitter-Collector Breakdown Voltage	I <sub>E</sub> =100µA E <sub>e</sub> =0mW/cm²	-	5	-	V	
VCE(sat)	Collector-Emitter Saturation Voltage	Ic=2mA Ee=1mW/cm²	-	-	0.4	V	
ICEO	Collector Dark Current	VCE=20V Ee=0mW/cm²	-	-	100	nA	
Ic(on)	On State Collector Current	Ee=1mW/cm <sup>2</sup> $\lambda_P$ =940nm, $V_{CE}$ =5V	0.1	0.5	0.8	mA	
tr	Rise Time	Vce=5V, Ic=1mA	-	15	-	uS	4
tf	Fall Time	RL=1000Ω	-	15	-	uS	4

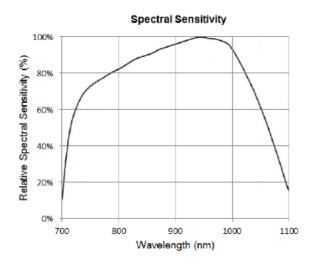
## **Notes**

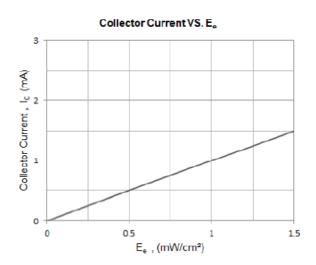
#### 4. Test circuit:

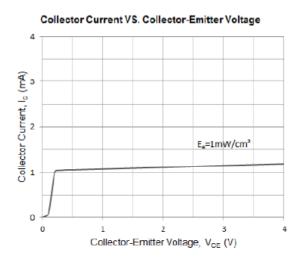




# **Typical Characteristic Curves**





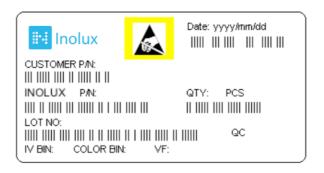




# **Ordering Information**

Product	Symbol	Parameters	Test conditions	Min	Тур	Max	Units	Orderable Part Number
IN-S126BTNPT	IC(ON)	On State Collector Current	Ee=1mW/cm <sup>2</sup> $\lambda_P$ =940nm, $V_{CE}$ =5V	0.1	0.5	0.8	mA	IN-S126BTNPT

# **Label Specifications**



## Inolux P/N:

I	N	-	S	126	В	Т	N	PT	-	-	-	-	-
			Material	Package	Variation	Orientation	Lens	Color			ıstor tam <sub>l</sub>		
Ino SM			PCB - S	126B = 120 molder		T = Top Mount	N = Black	PT = Photo Transistor					

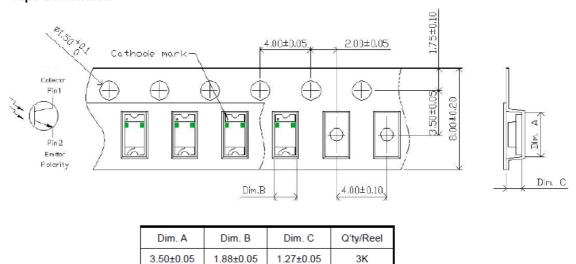
#### Lot No.:

Z	2	0	1	7	01	24	001
Internal		Year (2017	2019 \	Month	Date	Serial	
Tracker		rear (2017)	, 2010,)	WIGHTH	Date	Seriai	



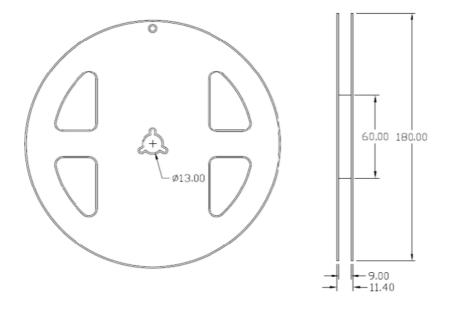
# **Packaging Information:**

## **Packaging Tape Dimension**



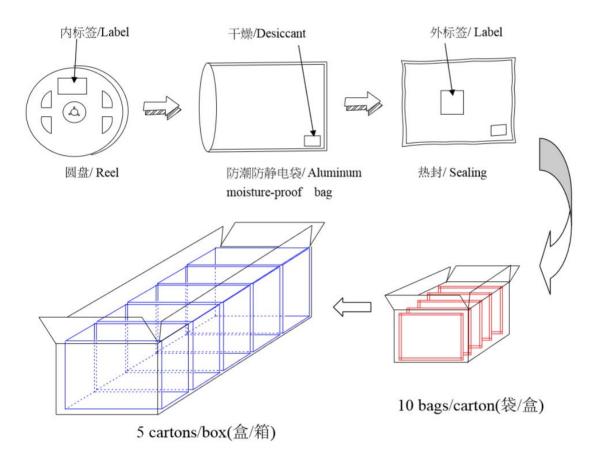
1.27±0.05

## **Reel Dimension**





# **Packing Dimension**



5 boxes per carton are available depending on shipment quantity.

	Specification	Material	Quantity
Carrier tape	Per EIA 481-1A specs	Conductive black tape	3000pcs per reel
Reel	Per EIA 481-1A specs	Conductive black	
Label	IN standard	Paper	
Packing bag	220x240mm	Aluminum laminated bag/ no-zipper	One reel per bag
Carton	IN standard	Paper	Non-specified
Othoro:			

Each immediate box consists of 5 reels. The 5 reels may not necessarily have the same lot number or the same bin. Each reel has a label identifying its specification; the immediate box consists of a product label as well.

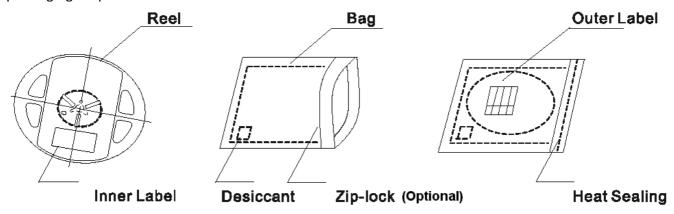


# **Dry Pack**

All SMD optical devices are **MOISTURE SENSITIVE**. Avoid exposure to moisture at all times during transportation or storage. Every reel is packaged in a moisture protected anti-static bag. Each bag is properly sealed prior to shipment.

Upon request, a humidity indicator will be included in the moisture protected anti-static bag prior to shipment.

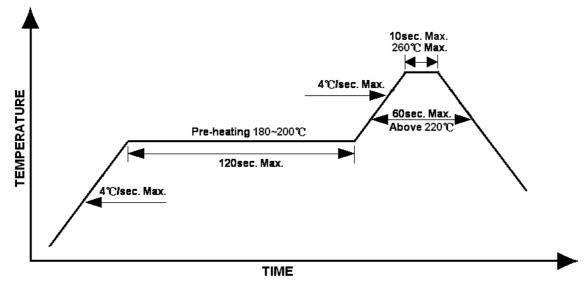
The packaging sequence is as follows:



# **Reflow Soldering**

- Recommended tin glue specifications: melting temperature in the range of 178~192 °C
- The recommended reflow soldering profile is as follows (temperatures indicated are as measured on the surface of the LED resin):







#### **Precautions**

- Avoid exposure to moisture at all times during transportation or storage.
- Anti-Static precaution must be taken when handling GaN, InGaN, and AllnGaP products.
- It is suggested to connect the unit with a current limiting resistor of the proper size. Avoid applying a reverse voltage.
- Avoid operation beyond the limits as specified by the absolute maximum ratings.
- · Avoid direct contact with the surface through which the LED emits light.
- If possible, assemble the unit in a clean room or dust-free environment.

## Reworking

- Rework should be completed within 5 seconds under 260 °C.
- The iron tip must not come in contact with the copper foil.
- Twin-head type is preferred.

# Cleaning

Following are cleaning procedures after soldering:

- An alcohol-based solvent such as isopropyl alcohol (IPA) is recommended.
- Temperature x Time should be 50°C x 30sec. or <30°C x 3min
- Ultra sonic cleaning: < 15W/ bath; bath volume ≤ 1liter
- Curing: 100 °C max, <3min</li>

#### **Cautions of Pick and Place**

- Avoid stress on the resin at elevated temperature.
- Avoid rubbing or scraping the resin by any object.
- Electro-static may cause damage to the component. Please ensure that the equipment is properly grounded. Use of an ionizer fan is recommended.





Reliability

Failures	lability					
Precondition	Item	Frequency/ lots/ samples/	Standards	Conditions		
Precondition         monitoring tests according to JEDEC Level 2         2.) Moisture storage at 85°C/ 60% R.H. for 168hrs           Solderability         1Q/ 1/ 22/ 0         JESD22-B102-B And CNS-5068         Accelerated aging 155°C/ 24hrs Tinning speed: 2.5+0.5cm/s Tinning: A: 215°C/ 3+1s or B: 260°C/ 10+1s           Resistance to soldering heat         CNS-5067         Dipping soldering terminal only Soldering bath temperature A: 260+/-5°C; 10+/-1s B: 350+/-10°C; 3+/-0.5s           Operating life test         1Q/ 1/ 40/ 0         CNS-11829         1.) Precondition: 85°C baking for 24hrs 85°C/ 60% R.H. for 168hrs 2.) Tamb25°C; IF=20mA; duration 1000hrs           High humidity, high temperature bias         1Q/ 1/ 45/ 0         JESD-A101-B         Tamb: 55°C Humidity: 85% R.H., IF=5mA Duration: 1000hrs           High temperature bias         1Q/ 1/ 20         IN specs.         Tamb: 55°C IF=20mA, Duration: 1000hrs           Pulse life test         1Q/ 1/ 40/ 0         JESD-A104-A IEC 68-2-14, Nb         Tamb25°C, If=20mA, Ip=100mA, Duty cycle=0.125 (tp=125 μ s,T=1sec) Duration 500hrs)           Temperature cycle         1Q/ 1/ 76/ 0         JESD-A104-A IEC 68-2-14, Nb         A cycle: -40 degree C 15min; +85 degree C 15min. 300 cycles 2 chamber/ Air-to-air type           High humidity         1Q/ 1/ 40/ 0         CNS-6117         60+3°C						
10   10   10   10   10   10   10   10		For all reliability	J-STD-020			
Solderability	Precondition	monitoring tests according		2.) Moisture storage at 85°C/ 60% R.H. for		
Solderability		to JEDEC Level 2		168hrs		
And CNS-5068   Tinning speed: 2.5+0.5cm/s   Tinning: A: 215°C/ 3+1s or B: 260°C/ 10+1s			JESD22-B102-B	Accelerated aging 155°C/ 24hrs		
Tinning: A: 215°C/ 3+1s or B: 260°C/ 10+1s	Solderability		And CNS-5068			
CNS-5067   Dipping soldering terminal only   Soldering bath temperature   A: 260H/-5°C; 10+/-18   B: 350H/-10°C; 3+/-0.5s	,					
Resistance to soldering heat   Soldering bath temperature   A: 260+/-5°C; 10+/-1s   B: 350+/-10°C; 3+/-0.5s			CNS-5067			
Soldering heat   A: 260+/-5°C; 10+/-1s   B: 350+/-10°C; 3+/-0.5s	Resistance to					
B: 350+/-10°C; 3+/-0.5s						
CNS-11829       1.) Precondition: 85°C baking for 24hrs 85°C/60%R.H. for 168hrs 2.) Tamb25°C; IF=20mA; duration 1000hrs         High humidity, high temperature bias       1Q/ 1/ 45/ 0       JESD-A101-B       Tamb: 85°C Humidity: 85% R.H., IF=5mA Duration: 1000hrs         High temperature bias       1Q/ 1/ 20       IN specs.       Tamb: 55°C IF=20mA Duration: 1000hrs         Pulse life test       1Q/ 1/ 40/ 0       Tamb25°C, If=20mA,, Ip=100mA, Duty cycle=0.125 (tp=125 μ s,T=1sec) Duration 500hrs)         Temperature cycle       1Q/ 1/ 76/ 0       JESD-A104-A IEC 68-2-14, Nb       A cycle: -40 degree C 15min; +85 degree C 15min; +85 degree C 15min         High humidity       1Q/ 1/ 40/ 0       CNS-6117       60+3°C	Soldering fleat					
Operating life test         85°C/ 60%R.H. for 168hrs           High humidity, high temperature bias         1Q/ 1/ 45/ 0           High temperature bias         1Q/ 1/ 20           High temperature bias         IN specs.           Tamb: 55°C   Humidity: 85% R.H., IF=5mA   Duration: 1000hrs           IN specs.         Tamb: 55°C   IF=20mA   Duration: 1000hrs           Tamb25°C, If=20mA, Ip=100mA, Duty   cycle=0.125 (tp=125 μ s,T=1sec)   Duration 500hrs)           Temperature cycle         1Q/ 1/ 76/ 0           JESD-A104-A   IEC 68-2-14, Nb         A cycle: -40 degree C 15min; +85 degree C 15min   Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air type           High humidity         1Q/ 1/ 40/ 0         CNS-6117           60+3°C		10/1/40/0	CNS-11829			
Comparison   Co	Operating life test	19/1/40/0	0110-11029			
High humidity, high temperature bias1Q/ 1/ 45/ 0JESD-A101-BTamb: 85°C Humidity: 85% R.H., IF=5mA Duration: 1000hrsHigh temperature bias1Q/ 1/ 20IN specs.Tamb: 55°C IF=20mA Duration: 1000hrsPulse life test1Q/ 1/ 40/ 0Tamb: 25°C, If=20mA, Ip=100mA, Duty cycle=0.125 (tp=125 μ s,T=1sec) Duration 500hrs)Temperature cycle1Q/ 1/ 76/ 0JESD-A104-A IEC 68-2-14, NbA cycle: -40 degree C 15min; +85 degree C 15min Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air typeHigh humidity1Q/ 1/ 40/ 0CNS-611760+3°C	Operating the test					
high temperature biasHumidity: 85% R.H., IF=5mA Duration: 1000hrsHigh temperature bias1Q/ 1/ 20IN specs.Tamb: 55°C IF=20mA Duration: 1000hrsPulse life test1Q/ 1/ 40/ 0Tamb25°C, If=20mA,, Ip=100mA, Duty cycle=0.125 (tp=125 μ s,T=1sec) Duration 500hrs)Temperature cycle1Q/ 1/ 76/ 0JESD-A104-A IEC 68-2-14, NbA cycle: -40 degree C 15min; +85 degree C 15min Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air typeHigh humidity1Q/ 1/ 40/ 0CNS-611760+3°C		10/1/15/0	1505 4404 5			
bias         Duration: 1000hrs           High temperature bias         1Q/ 1/ 20         IN specs.         Tamb: 55°C IF=20mA Duration: 1000hrs           Pulse life test         1Q/ 1/ 40/ 0         Tamb25°C, If=20mA,, Ip=100mA, Duty cycle=0.125 (tp=125 μ s,T=1sec) Duration 500hrs)           Temperature cycle         1Q/ 1/ 76/ 0         JESD-A104-A IEC 68-2-14, Nb         A cycle: -40 degree C 15min; +85 degree C 15min; +85 degree C 15min Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air type           High humidity         1Q/ 1/ 40/ 0         CNS-6117         60+3°C		1Q/ 1/ 45/ 0	JESD-A101-B			
High temperature bias       1Q/ 1/ 20       IN specs.       Tamb: 55°C IF=20mA Duration: 1000hrs         Pulse life test       1Q/ 1/ 40/ 0       Tamb25°C, If=20mA,, Ip=100mA, Duty cycle=0.125 (tp=125 μ s,T=1sec) Duration 500hrs)         Temperature cycle       1Q/ 1/ 76/ 0       JESD-A104-A IEC 68-2-14, Nb       A cycle: -40 degree C 15min; +85 degree C 15min Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air type         High humidity       1Q/ 1/ 40/ 0       CNS-6117       60+3°C	,					
Figh temperature bias   IF=20mA   Duration: 1000hrs	bias					
bias       IF=20mA Duration: 1000hrs         1Q/ 1/ 40/ 0       Tamb25°C, If=20mA, Ip=100mA, Duty cycle=0.125 (tp=125 μ s,T=1sec) Duration 500hrs)         1Q/ 1/ 76/ 0       JESD-A104-A IEC 68-2-14, Nb       A cycle: -40 degree C 15min; +85 degree C 15min Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air type         High humidity       1Q/ 1/ 40/ 0       CNS-6117       60+3°C	High tomporature	1Q/ 1/ 20	IN specs.	Tamb: 55°C		
Duration: 1000hrs         1Q/ 1/ 40/ 0       Tamb25°C, If=20mA,, Ip=100mA, Duty cycle=0.125 (tp=125 μ s,T=1sec) Duration 500hrs)         Temperature cycle       JESD-A104-A IEC 68-2-14, Nb       A cycle: -40 degree C 15min; +85 degree C 15min Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air type         High humidity       1Q/ 1/ 40/ 0       CNS-6117       60+3°C				IF=20mA		
Pulse life test cycle=0.125 (tp=125 $\mu$ s,T=1sec) Duration 500hrs)  Temperature cycle life test pulse life test cycle cycle life test cycle cyc	bias			Duration: 1000hrs		
Pulse life test		1Q/ 1/ 40/ 0		Tamb25°C, If=20mA,, Ip=100mA, Duty		
Temperature cycle  High humidity  1Q/ 1/ 76/ 0  Duration 500hrs)  A cycle: -40 degree C 15min; +85 degree C 15min Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air type  CNS-6117  Duration 500hrs)  A cycle: -40 degree C 15min; +85 degree C 15min Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air type	Pulse life test					
Temperature cycle  1Q/ 1/ 76/ 0  JESD-A104-A IEC 68-2-14, Nb  15min  Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air type  High humidity  1Q/ 1/ 40/ 0  JESD-A104-A IEC 68-2-14, Nb  15min  Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air type  60+3°C				,		
Temperature cycle  IEC 68-2-14, Nb  15min Thermal steady within 5 min 300 cycles 2 chamber/ Air-to-air type  High humidity  1Q/ 1/ 40/ 0  CNS-6117  60+3°C		10/ 1/ 76/ 0	JESD-A104-A			
Thermal steady within 5 min  300 cycles  2 chamber/ Air-to-air type  High humidity 1Q/ 1/ 40/ 0 CNS-6117 60+3°C		1 47 17 197 5				
300 cycles   2 chamber/ Air-to-air type   High humidity   1Q/ 1/ 40/ 0   CNS-6117   60+3°C			120 00 2 14, 145	-		
2 chamber/ Air-to-air type	cycle					
High humidity 1Q/ 1/ 40/ 0 CNS-6117 60+3°C						
	1.12.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.1.	10/1/10/0	010 0447			
istorage test 1 190±5/-10% R H for 500hrs		TQ/ 1/ 40/ 0	UNS-611/			
	storage test			90+5/-10% R.H. for 500hrs		
High temperature   1Q/ 1/ 40/ 0   CNS-554   100+10°C for 500hrs		1Q/ 1/ 40/ 0	CNS-554	100+10°C for 500hrs		
storage test	storage test					
Low temperature   1Q/ 1/ 40/ 0   CNS-6118   -40+5°C for 500hrs	Low temperature	1Q/ 1/ 40/ 0	CNS-6118	-40+5°C for 500hrs		
storage test						



# IN-S126BTNPT Phototransistor Top View SMD 1206 PCB Type

**Revision History** 

Changes since last revision	Page	Version No.	Revision Date
Initial Release		1.0	01-31-2019

#### **DISCLAIMER**

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- 2. A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.